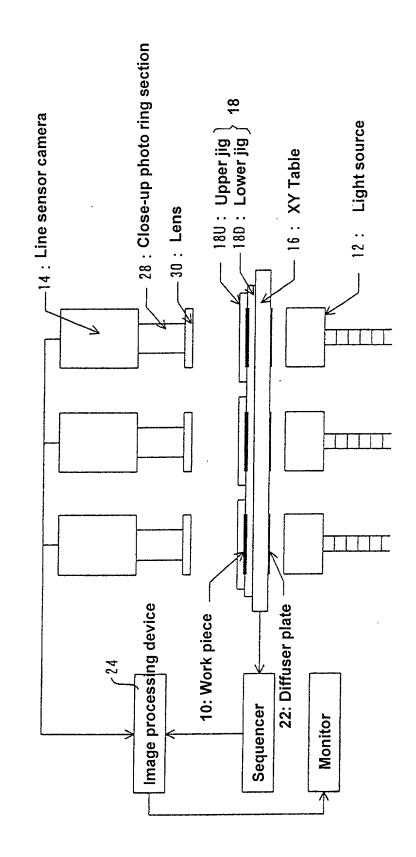
Fig. 1



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Title: METHOD FOR EXAMINING FOREIGN MATTERS IN THROUGH HOLES Inventor: GOTO, et al Atty. Ref. No.: 9319S-000197

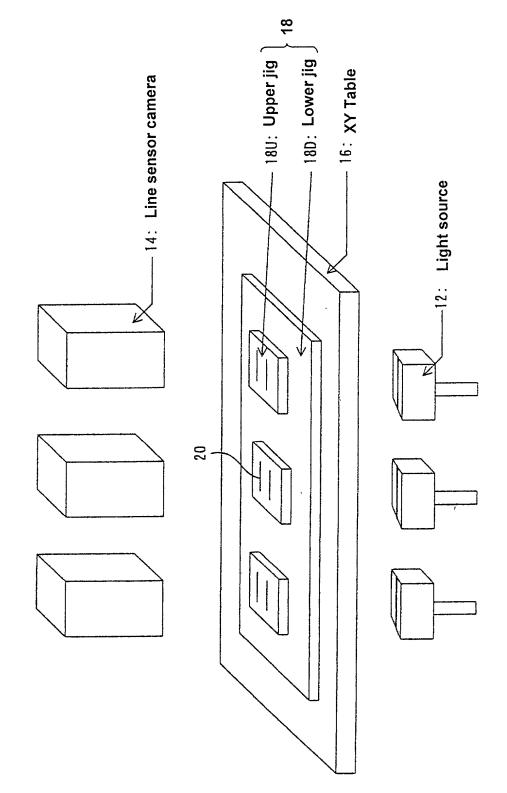
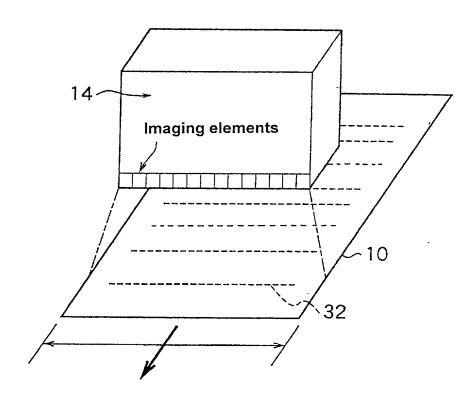
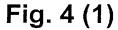
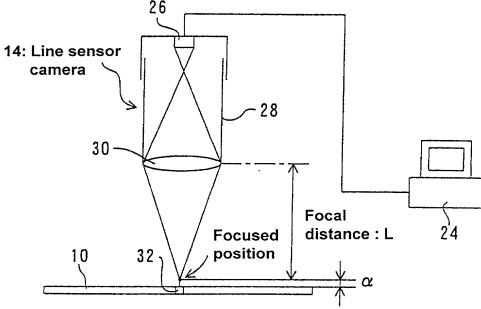


Fig. 3



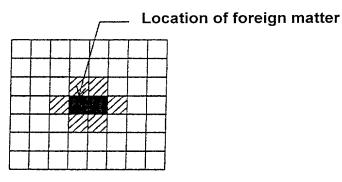
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Out-of-focus state (work piece surface +  $\alpha$ )

Fig. 4 (2)

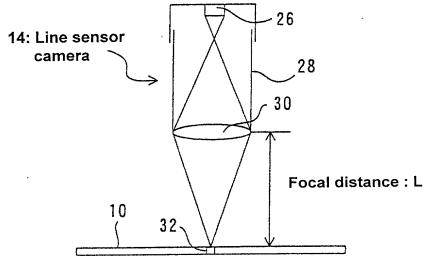


**Out-of-focus condition** 

(Size of foreign matter: 8 pixels)

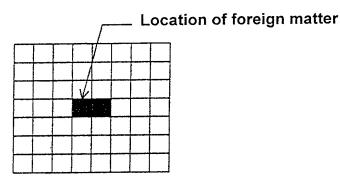
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Fig. 5 (1)



Focused state (work piece surface)

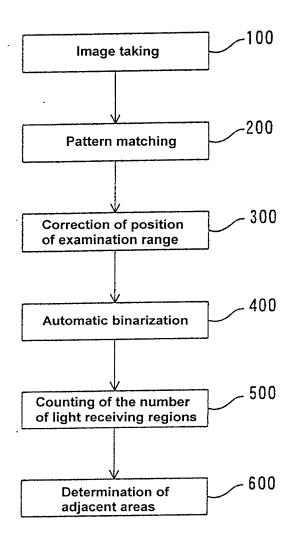
Fig. 5 (2)



**Focused condition** 

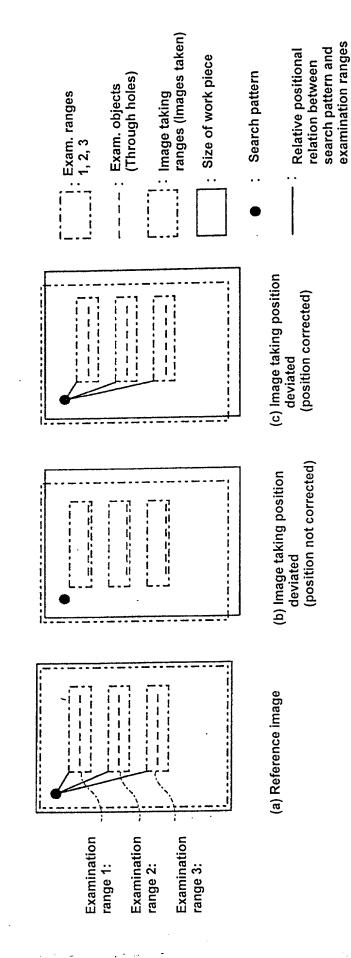
(Size of foreign matter: 2 pixels)

Fig. 6



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# Fia. 7



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Fig. 8 (1)

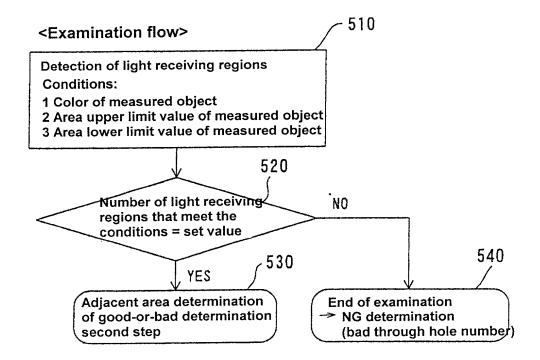
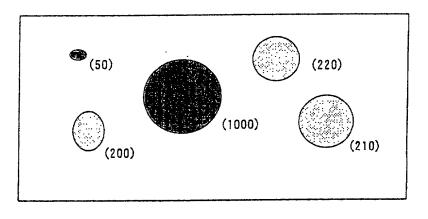


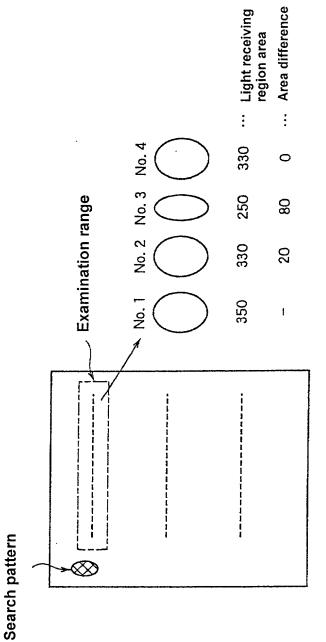
Fig. 8 (2)

<Description of area upper limit values and area lower limit values of measured objects>



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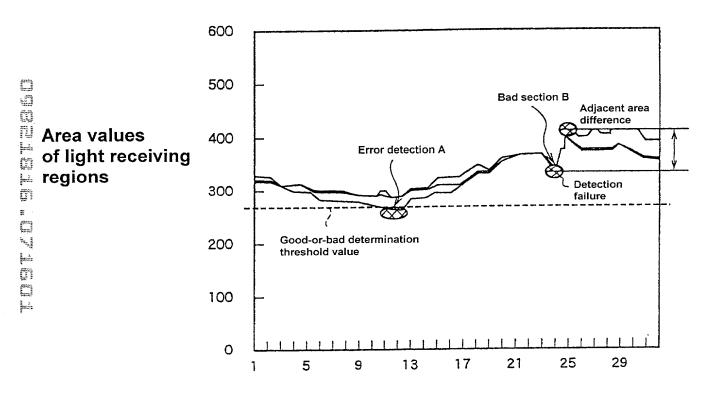


ex) Bad if area difference is 50 or over

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Fig. 10



Position of through holes

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Fig. 11

### << Flow of adjacent area determination>>

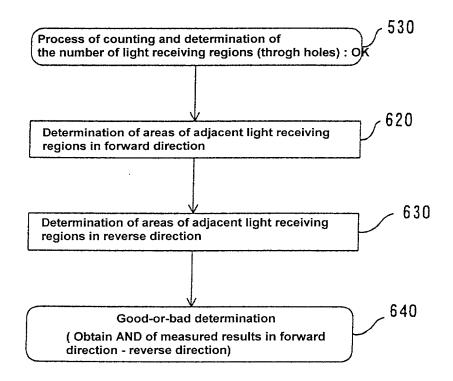
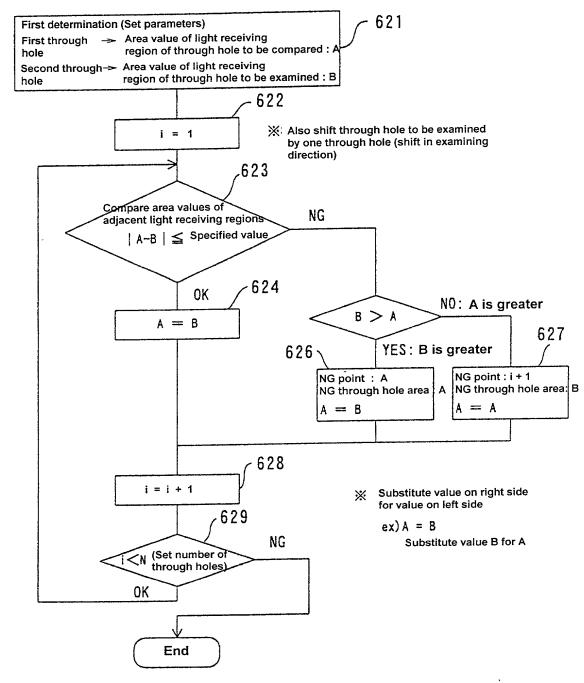


Fig. 12

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## << Flow of adjacent area determination process and Examination of each examination range>>



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Fig. 13 (1)

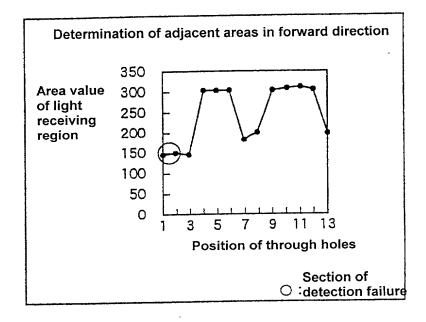
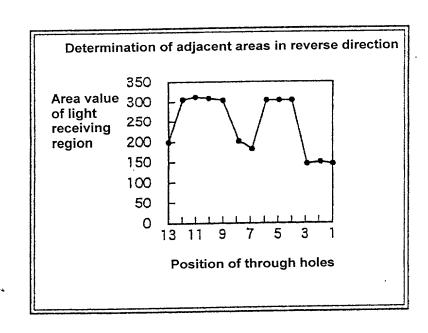


Fig. 13 (2)



1

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Fig. 14

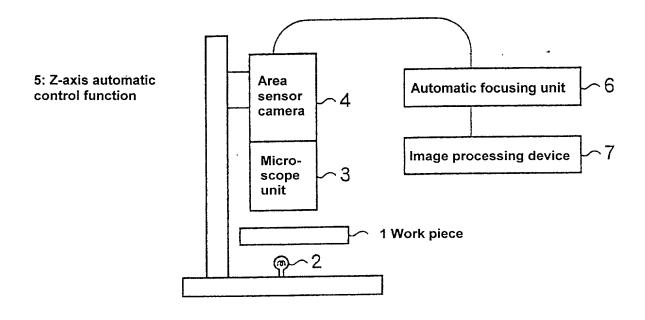


Fig. 15

